

# CENTER FOR NANOSCALE MATERIALS SCIENTIFIC CONTACTS

## Nanofabrication and Devices

**Anirudha Sumant (Group Leader)**.....sumant@anl.gov  
superlubricity, diamond-based NEMS, CNT, graphene  
wear/friction measurements

**Jithin Cherunilam**.....jcherunilam@anl.gov  
cleanroom coordinator

**David Czaplewski**.....dczaplewski@anl.gov  
MEMS/NEMS, electron beam lithography, CVD

**Ralu Divan**.....divan@anl.gov  
electron beam lithography, nanogels, MEMS/NEMS

**Xu Han**.....xu.han@anl.gov  
high-frequency piezo-optomechanical spectroscopy, CVD,  
ultralow temperature/strong magnetic field measurement,  
FIB/SEM dual beam imaging and patterning

**Yizhong Huang**.....huangy@anl.gov  
cryogenic quantum measurements, laser spectroscopy, photonics,  
EPR, photolithography, SEM

**C. Suzanne Miller**.....csmiller@anl.gov  
XeF<sub>2</sub>, evaporation, RTP, dicing saw

**Dongjea Seo**.....dseo@anl.gov

### MAJOR TOOLS

- JEOL 8100FS, 100kV electron beam lithography
- Raith 150, 30kV electron beam lithography
- FEI Nova 600 NanoLab DualBeam FIB/SEM
- Karl Suss MA6 Optical mass aligner
- ASML PAS 5000 wafer stepper
- Direct write optical lithography
- Interferometric lithography
- Xactix XeF<sub>2</sub> etcher
- BlueFors LD400 10mK Dilution Refrigerator System
- AMI 5-1-1Telsa Vector Magnet
- Wet chemistry & metrology
- Bruker FastScan AFM
- Deposition (Temescal ebeam evaporators, AJAs, atomic layer deposition (ALD), etc.)
- Lambda microwave plasma CVD nanocrystalline diamond
- Thermal/PECVD for CNT/graphene synthesis
- Tribometer for friction and wear measurements
- Sonotek Ultrasonic Spray Coating System
- Piezo-Optomechanical Spectrometer (POMS)

## Nanoscale Synthesis and Characterization

**Jeffrey Guest (Group Leader)** .....jrguest@anl.gov  
STM, laser spectroscopy, ambient AFM, EPR

**Nathan Guisinger** .....nguisinger@anl.gov  
UHV STM, AFM, 2-D materials, STS, cryo-STM

**Gengnan Li** .....lig@anl.gov  
2D materials; thermocatalysis; electrocatalysis; in situ/operando spectroscopy

**Xiao-Min Lin**.....xmlin@anl.gov  
synthesis of nanocrystals, TGA/DSC, rotating disk electrode,  
rheometry at Sector 8 of APS, glovebox

**John Pearson** .....pearson@anl.gov  
XRD, magnetometry

**Dan Rosenmann**.....rosenmann@anl.gov  
evaporation, deposition, sputtering

**Nozomi Shirato**.....nshirato@anl.gov  
X-ray scanning tunneling microscopy, XRD

### MAJOR TOOLS

- UHV SPM (AFM/STM) (Omicron)
- VT-AFM (Omicron XA) with optical access
- Createc LT-STM
- Cryo-STM w/magnetic field
- Scanning probe microscope, AFM (Veeco)
- Kurt Lesker electron beam evaporator and sputtering, deposition
- Agilent ICP-OES
- FT-IR w/ Hyperion Microscope
- Magnetometry (QD PPMS & MPMS)
- TGA/DSC
- Luminescence/UV-vis-NIR
- X-ray diffractometer (Bruker D2 & D8)
- Integrated glovebox system
- RheoXPCS/SAXS at Sector 8 of APS

### CONTACT

**Gary Wiederrecht**

Interim Director

Phone: 630-252-4586

Email: wiederrecht@anl.gov

**Connie Pfeiffer**

User Program Manager

Phone: 630-252-6952

Email: cpfeiffer@anl.gov or  
cnm\_useroffice@anl.gov

## Theory and Modeling

### Subramanian Sankaranarayanan (Group Leader)

ssankaranarayanan@anl.gov  
nanoscale oxide energy materials, machine learning

**Henry Chan**.....hchan@anl.gov  
multi-scale modeling, soft materials, AI/ML for imaging and inverse design, scientific software development

**Maria Chan**.....mchan@anl.gov  
photovoltaics, photocatalysts, thermoelectrics, batteries, informatics, atomistic modeling integration w/expt

**Pierre Darancet** .....pdarancet@anl.gov  
charge and energy transport, optoelectronics; exciton dynamics

**Stephen Gray**.....gray@anl.gov  
nanophotonics, electrodynamics

**Michael Sternberg**.....sternberg@anl.gov  
software development

**Katerina Vriza**.....avriza@anl.gov  
AI/ML for molecular materials, cheminformatics, data mining, laboratory automation, high-throughput simulations

## Nanophotonics and Biofunctional Structures

Richard Schaller (Group Leader) ..... schaller@anl.gov  
transient absorption/emission spectroscopy, solar energy

Benjamin Diroll..... bdiroll@anl.gov  
synthesis, time-resolved spectroscopy

Chris Fry..... hfry@anl.gov  
synthesis, peptide synthesis, HPLC, CD, EPR

David Gosztola..... gosztola@anl.gov  
lasers, Raman microscopy

Xuedan Ma..... xuedan.ma@anl.gov  
single molecule/particle spectroscopy

Elena Rozhkova..... rozhkova@anl.gov  
bio(in)organic, biological chemistry, synthetic biology, GC/MS

Elena Shevchenko ..... eshevchenko@anl.gov  
2-D and 3-D nanoparticle assembly, SEM

Jie Xu..... xuj@anl.gov  
modular robotic workflow for synthesis and processing, polymer processing, wearable electronic devices

## Electron and X-ray Microscopy

**Martin Holt (Group Leader)**..... mvholt@anl.gov  
X-ray diffraction, ptychography and fluorescence

### Electron Microscopy

**Daniel Durham**..... durhamd@anl.gov  
TEM, STEM, UEM, in-situ

**Tom Gage** ..... tgage@anl.gov  
Ultrafast electron microscopy (UEM)

**Rachel Koritala**..... koritala@anl.gov  
SEM/TEM trainer

**Haihua Liu**..... haihua.liu@anl.gov  
UEM, TEM, STEM, EELS, SAED

**Yuzi Liu**..... yuziliu@anl.gov  
analytical TEM, in situ TEM

**Jianguo Wen**..... jwen@anl.gov  
ACAT, TEM, batteries, PV

### Synchrotron X-ray Microscopy

**Rui Liu** ..... rui.liu@anl.gov  
X-ray diffraction, nanoimaging, in-situ/in operando experiments

**Tao Zhou** ..... tzhou@anl.gov  
X-ray diffraction

## MAJOR TOOLS

- Nanoscience Computational Facility 30 TFlop cluster for:
  - Density-functional-based tight-binding
  - Time-domain nanophotonics simulation
  - MPI-based parallel versions of nanophotonics and tight-binding codes
- GPAW; real space, grid-based DFT-PAW
- Access to Argonne computer facilities
- Support for experimental projects
- Support for theoretical projects
- (DFTB) electronic structure package
- BLAST
- FANTASTX

## MAJOR TOOLS

- Ultrafast transient absorption spectroscopy
- Confocal Raman microscope, Renishaw
- VIS/NIR microscopy
- Time-resolved emission spectroscopy
- Time-correlated single photon counting
- UV-to-TH<sub>3</sub> ultrafast spectroscopy
- Single photon microscope for optics
- Fluorescence spectroscopy
- Field-emission SEM (JEOL JSM7500F)
- Adiabatic demagnetization refrigerator (ADR)
- Functionalization, electro/photo-chemical
- HPLC, GCMS
- Laser Scanning Confocal Microscope (Zeiss)
- Post-self-assembly processing
- ZetaSizer Nano, Malvern
- Solar simulator, QEMS (Oriel)
- FTIR (Thermo-Nicolet)
- Synthesis & surface modification of nanoparticles
- Magneto-Electrical-Optical Spectrometer
- Microfluidic Droplet Generation and Imaging

## MAJOR TOOLS

### Electron Microscopy

- UEM: Ultrafast Electron Microscopy
- FEI Quanta 400F environmental and variable-pressure SEM
- FEI Talos F200X TEM/STEM
- FEI Tecnai F20ST TEM/STEM
- Field-emission TEM (JEOL 2100F)
- Hitachi S-4700-II high-vacuum SEM
- JEOL IT800HL SEM
- TFS Spectra 200
- Zeiss 1540XB FIB-SEM

### X-ray Microscopy

- Hard X-ray nanoprobe beamline, Sector 26 of APS
- Scanning nanodiffraction and ptychography
- Chemical and structural nanoimaging
- Heating/cooling specimen stage
- 20-30 nm resolution, 6-12 keV
- In situ/in operando experiments